

[prob. 1] (The exact numbers can be different for prob 1 & prob 2)

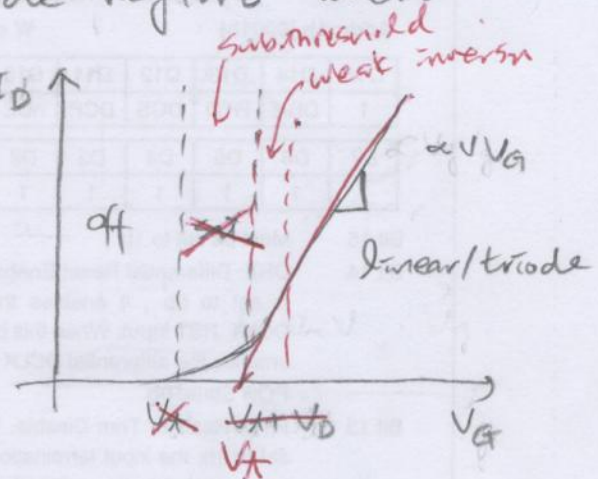
(a) The devices are in the triode region when

$$V_G \geq V_T + V_D = V_T + 50mV$$

$$I_D = K \cdot \frac{W}{L} \cdot \left[ (V_G - V_T) \cdot V_D - \frac{V_D^2}{2} \right]$$

$$\approx K \cdot \frac{W}{L} \cdot V_D (V_G - V_T)$$

$\xrightarrow{2.5mm}$   $\xrightarrow{0.3mm}$  slope,  $M$ .



$$M_{NMOS} = K_n \cdot \frac{2.5mm}{0.3mm} \cdot 50mV = \frac{8M - 2M}{0.8V - 0.6V}$$

$$\therefore K_n = \frac{8M - 2M}{0.8 - 0.6} \cdot \frac{0.3}{2.5} \cdot \frac{1}{50m} \approx \underline{\underline{72.0 \mu A/V^2}}$$

$$M_{PMOS} = K_p \cdot \frac{2.5mm}{0.3mm} \cdot 50mV = \frac{4M - 2M}{1.0V - 0.8V}$$

$$\therefore K_p = \frac{4M - 2M}{1.0 - 0.8} \cdot \frac{0.3}{2.5} \cdot \frac{1}{50m} \approx \underline{\underline{24.0 \mu A/V^2}}$$

(b) From Fig. 5,

$$|V_T| = |V_{T0}| + \gamma \left( \sqrt{2|\phi_f| + |V_{SB}|} - \sqrt{2|\phi_f|} \right)$$

$ V_{SB} $	$ V_{T,n} $	$ V_{T,p} $ $\xrightarrow{V_{T0}}$
0	0.45V	0.50V
1	0.65V	0.70V
2	0.75V	0.80V
3	0.80V	0.90V

$\gamma, \phi_f$  can be found by MATLAB's "fminsearch" (see appendix for codes)

$$\gamma_n = 0.21, \quad \phi_{f,n} = 4.3 \times 10^{-4} \approx 0$$

$$\gamma_p = 0.28, \quad \phi_{f,p} = 6.4 \times 10^{-5} \approx 0$$

Unrealistic values of  $\phi_s$  can be from either #2.  
 low doping concentration, inaccurate  $V_t$ , or measurement errors.

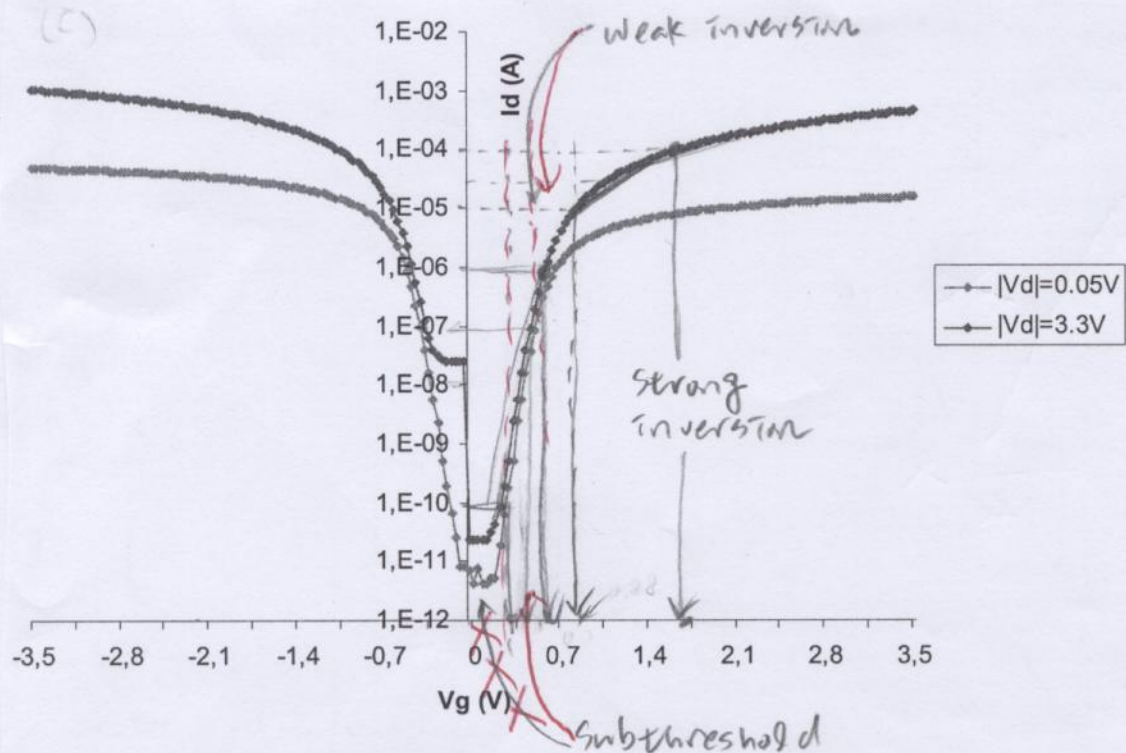


Fig. 6. PMOS and NMOS sub-threshold characteristics

(i) Strong inversion

$$g_m = \frac{10^{-4}A - 10^{-5}A}{1.75V - 0.88V} \approx 1.15 \times 10^{-4} S$$

$$\frac{g_m}{I_D} = \frac{1.15 \times 10^{-4} S}{5 \times 10^{-5} A} = 2.3 V^{-1}$$

(ii) weak inversion

$$g_m = \frac{10^{-6}A - 10^{-10}A}{0.7V - 0.35V} = 2.86 \times 10^{-6} S$$

$$\frac{g_m}{I_D} = \frac{2.86 \times 10^{-6} S}{5 \times 10^{-7} A} = 5.72 V^{-1}$$

(iii) subthreshold

~~$g_m \approx 0$~~   
 ~~$\frac{g_m}{I_D} \approx 0$~~

~~Probably because of the measurement accuracy limitation.~~

We can expect better efficiency from subthreshold and weak inversion than from strong inversion.

(d)	$ V_{gs} $	$I_{D, NMOS}$	$I_{D, PMOS}$
1		0.05 mA	0.02 mA
2		0.40 mA	0.15 mA
3		0.80 mA	0.35 mA
4		1.20 mA	0.55 mA

The devices look like linear devices, because of the velocity saturation.

(e) At  $|V_{gs}| = 3V$ , for example,

$$r_o = \frac{4.0V - 1.6V}{0.8mA - 0.75mA} = \underline{\underline{48K\Omega}}$$

$$r_o = \frac{1 + \lambda V_{DS}}{\lambda I_D} \Rightarrow \lambda = \frac{1}{r_o I_D - V_{DS}} \approx \underline{\underline{0.03}}$$

(f) Variation  $\hat{=} \frac{\text{max} - \text{min}}{\text{mode}}$

NMOS: % variation =  $\frac{0.5875V - 0.5125V}{0.5375V} \times 100 \approx \underline{\underline{14.0\%}}$

PMOS: " =  $\frac{0.5875V - 0.4875V}{0.5375V} \times 100 \approx \underline{\underline{18.6\%}}$

In Appendix C, we can see gradual changes of  $V_t$  across a wafer, while we can also observe some random effects that contribute to the  $V_t$  variations.

[pwb. 2]

(a) (i) NMOS

$$g_m \approx \frac{0.85mA - 0.4mA}{0.8V - 0.6V} = 2.25mS$$

$$r_o \approx \frac{1.0V - 0.5V}{0.75mA - 0.6mA} = 3.33K\Omega$$

$$\Rightarrow g_m r_o \approx \underline{\underline{7.5}}$$

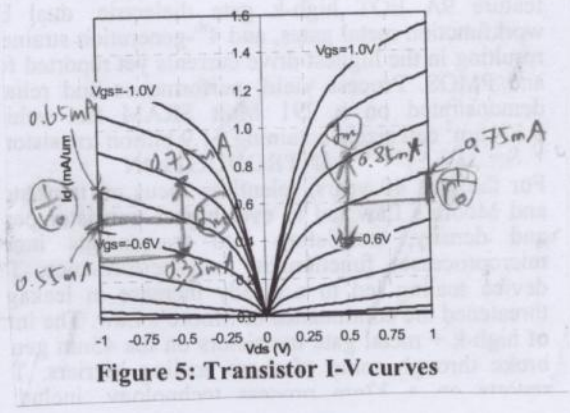
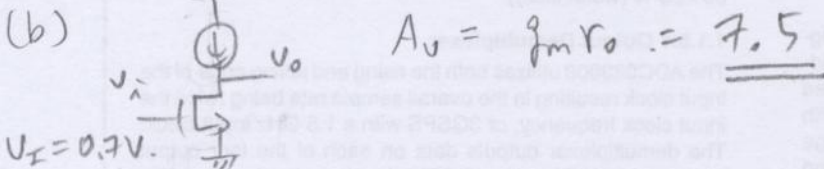


Figure 5: Transistor I-V curves

(i) PMOS

$$g_m \approx \frac{0.75 \text{ mA} - 0.35 \text{ mA}}{0.8 \text{ V} - 0.6 \text{ V}} = 2.0 \text{ mS} \quad \Rightarrow \quad g_{mro} \approx \underline{\underline{10.0}}$$

$$r_o \approx \frac{1.0 \text{ V} - 0.5 \text{ V}}{0.65 \text{ mA} - 0.55 \text{ mA}} = 5.0 \text{ k}\Omega$$



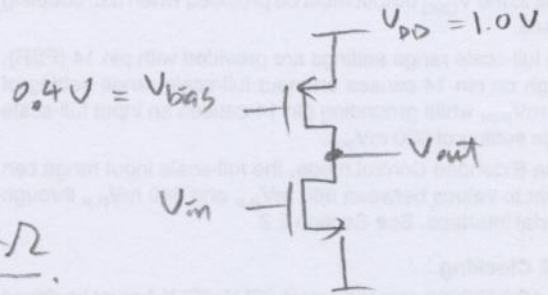
(c)  $(V_{GS, PMOS}) = 0.6 \text{ V}$

$$r_{op, V_{GS}=0.6 \text{ V}} \approx \frac{1.0 \text{ V} - 0.5 \text{ V}}{0.50 \text{ mA} - 0.35 \text{ mA}} = \underline{\underline{3.33 \text{ k}\Omega}}$$

$$g_{m, V_{GS}=0.6 \text{ V}} \approx \frac{0.55 \text{ mA} - 0.2 \text{ mA}}{0.7 \text{ V} - 0.5 \text{ V}} = \underline{\underline{1.75 \text{ mS}}}$$

Assume that  $V_{GS, N} = 0.7 \text{ V}$

$$\begin{aligned} A_v &= g_{m,n} (r_{op} \parallel r_{on}) \\ &= 2.25 \text{ mS} \cdot (3.33 \text{ k}\Omega \parallel 5.0 \text{ k}\Omega) \\ &= \underline{\underline{4.50}} \end{aligned}$$



Therefore, we cannot get high gains from transistors in advanced technology. *individual*

[prob. 3]  $I_m = K \left( \frac{W}{L} \right) V_{DSAT} \dots \textcircled{1}$

$$= \frac{2I_D}{V_{DSAT}} \dots \textcircled{2}$$

$$= \sqrt{2K \cdot \left( \frac{W}{L} \right) I_D} \dots \textcircled{3} \quad (\because \lambda = 0)$$

(a) From  $\textcircled{2}$ ,  $V_{DSAT} = \frac{2I_D}{g_m} = \frac{2 \times 1 \text{ mA}}{1 \text{ mS}} = \underline{2.0 \text{ V}}$

From  $\textcircled{1}$   $\left( \frac{W}{L} \right) = \frac{I_m}{V_{DSAT}} \cdot \frac{1}{K}$

$$\therefore \left( \frac{W}{L} \right)_n = \frac{1 \text{ mS}}{2.0 \text{ V}} \times \frac{1}{200 \mu\text{A}/\text{V}^2} = \underline{2.5} = \left( \frac{1.25 \text{ M}}{0.5 \text{ M}} \right)$$

$$\left( \frac{W}{L} \right)_p = \frac{1 \text{ mS}}{2.0 \text{ V}} \times \frac{1}{100 \mu\text{A}/\text{V}^2} = \underline{5.0} = \left( \frac{2.5 \text{ M}}{0.5 \text{ M}} \right)$$

(b) From  $\textcircled{2}$ ,  $I_D = \frac{g_m \cdot V_{DSAT}}{2} = \frac{1 \text{ mS} \cdot 0.2 \text{ V}}{2} = \underline{100 \mu\text{A}}$

From  $\textcircled{1}$ ,  $\left( \frac{W}{L} \right)_n = \frac{1 \text{ mS}}{0.2 \text{ V}} \cdot \frac{1}{200 \mu\text{A}/\text{V}^2} = \underline{25.0} = \left( \frac{12.5 \text{ M}}{0.5 \text{ M}} \right)$

$$\left( \frac{W}{L} \right)_p = \frac{1 \text{ mS}}{0.2 \text{ V}} \cdot \frac{1}{100 \mu\text{A}/\text{V}^2} = \underline{50.0} = \left( \frac{25 \text{ M}}{0.5 \text{ M}} \right)$$

(c) From  $\textcircled{3}$ ,  $I_D = \frac{I_m^2}{2 \cdot K \left( \frac{W}{L} \right)}$

$$I_{D,N} = \frac{(1 \text{ m})^2}{2 \cdot 200 \mu\text{A}/\text{V}^2 \cdot \frac{50}{0.5}} = \underline{25 \mu\text{A}}$$

$$I_{D,P} = \frac{(1 \text{ m})^2}{2 \cdot 100 \mu\text{A}/\text{V}^2 \cdot \frac{50}{0.5}} = \underline{50 \mu\text{A}}$$

From  $\textcircled{2}$ ,

$$V_{DSAT,N} = \frac{2 \cdot I_{D,N}}{g_m} = \frac{2 \times 25 \mu\text{A}}{1 \text{ mS}} = \underline{50 \text{ mV}}$$

$$V_{DSAT,P} = \frac{2 \cdot I_{D,P}}{g_m} = \frac{2 \times 50 \mu\text{A}}{1 \text{ mS}} = \underline{100 \text{ mV}}$$

(d) From ②,  $I_D = \frac{g_m \cdot V_{DSAT}}{2} \geq \frac{g_m \cdot V_{DSAT, min}}{2}$

$\therefore I_D \geq \frac{1mS \cdot 0.1V}{2} = \underline{\underline{50mA}}$

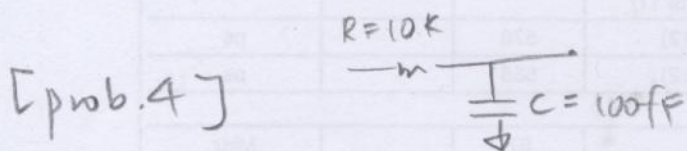
$(\frac{W}{L})_n = \frac{g_m}{K \cdot V_{DSAT, min}} = \frac{1mS}{200\mu A/V^2 \cdot 0.1V} = \underline{\underline{50}} = \left(\frac{25M}{0.5M}\right)$

$(\frac{W}{L})_p = \frac{1mS}{100\mu A/V^2 \cdot 0.1V} = \underline{\underline{100}} = \left(\frac{50M}{0.5M}\right)$

(e) From ①,  $(\frac{W}{L}) = \frac{g_m}{K \cdot V_{DSAT}} \geq \frac{g_m}{K \cdot V_{DSAT, max}}$

$V_{DSAT, max} = V_{DD} - V_t \cong 2.5V$

$(\frac{W}{L})_{min} = \frac{1mS}{200\mu A/V^2 \cdot 2.5V} = \underline{\underline{\left(\frac{1.0M}{0.5M}\right)}}$  (NMOS)

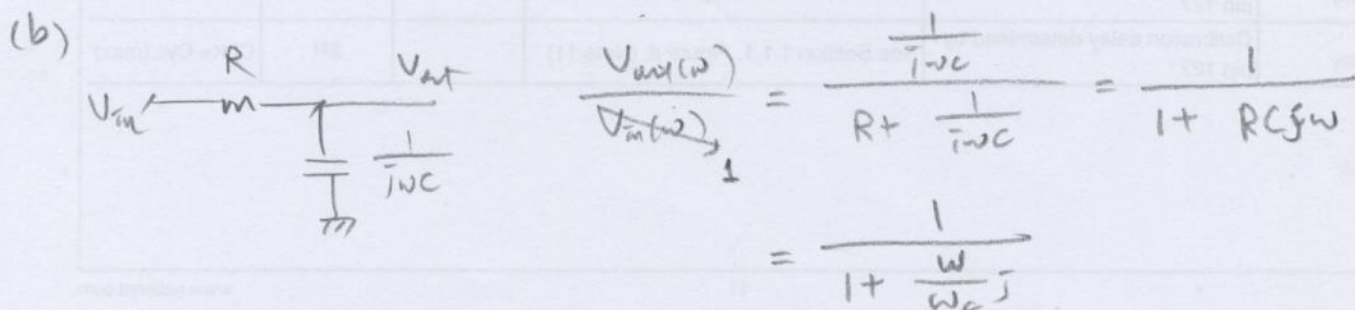


(a)  $\tau = RC = 10^{-9}s$

$R = \frac{1}{\omega_c C} \Rightarrow \omega_c = \frac{1}{RC} = 10^9 \text{ rad/s}$

$f_c = \frac{\omega_c}{2\pi} = 159.2 \text{ MHz}$

$\omega_c = \frac{1}{\tau}, f_c = \frac{\omega_c}{2\pi}, \tau = \frac{1}{\omega_c} = \frac{1}{2\pi f_c}$



$$V_{out}(0.1\omega_c) = \frac{1}{1+0.1j} = \frac{1}{\sqrt{1+(0.1)^2}} \angle -\arctan 0.1$$

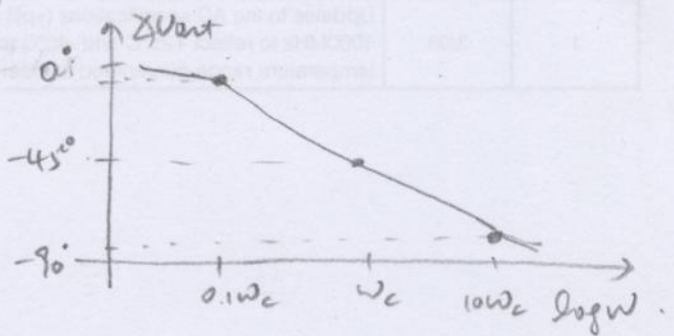
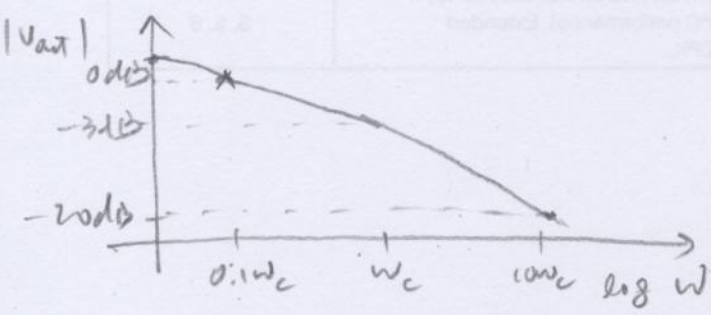
$$\approx 0.995 \angle -5.71^\circ \quad (-0.044\text{dB})$$

$$V_{out}(\omega_c) = \frac{1}{1+j} = \frac{1}{\sqrt{2}} \angle -\arctan 1$$

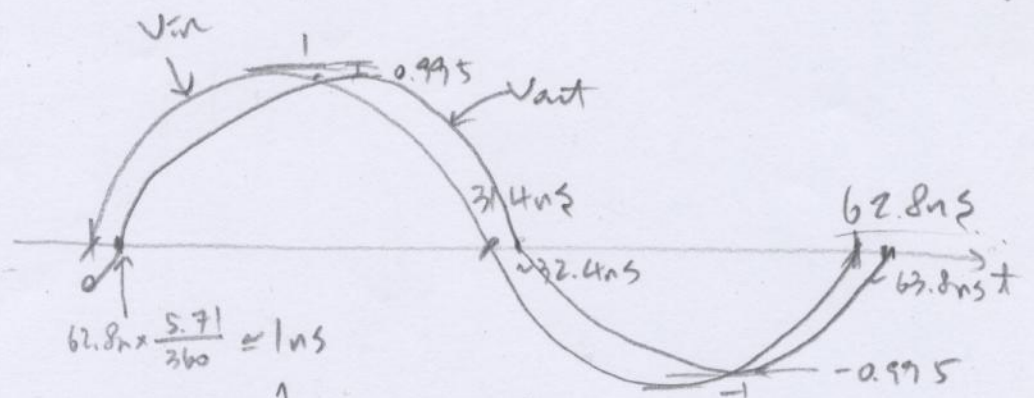
$$\approx 0.707 \angle -45^\circ \quad (-3\text{dB})$$

$$V_{out}(10\omega_c) = \frac{1}{1+10j} = \frac{1}{\sqrt{1+10^2}} \angle -\arctan 10$$

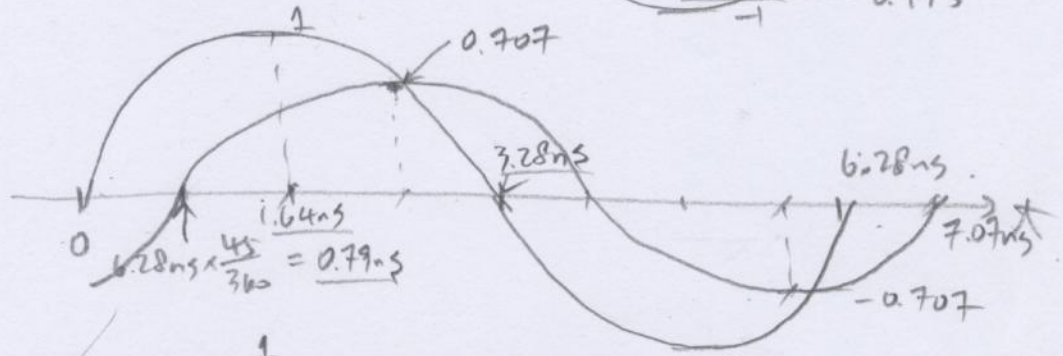
$$\approx 0.0995 \angle -84.3^\circ \quad (-20.0\text{dB})$$



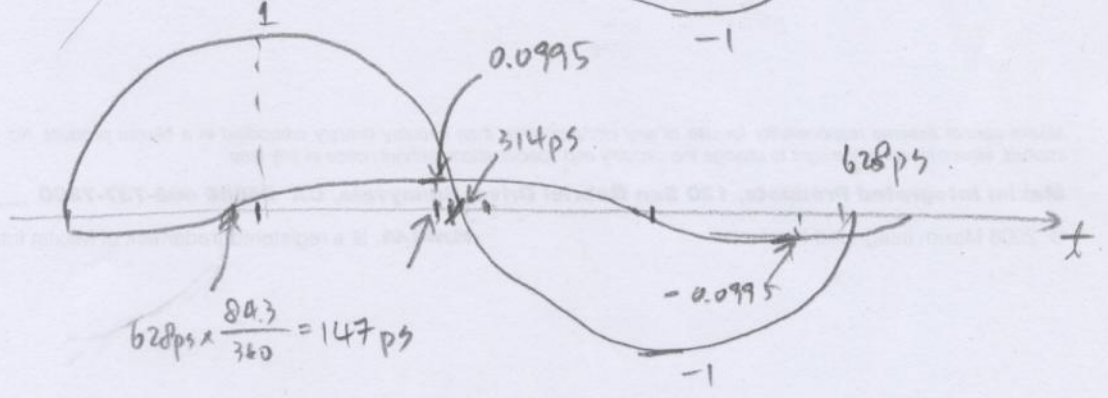
(i)  $0.1\omega_c$



(ii)  $\omega_c$



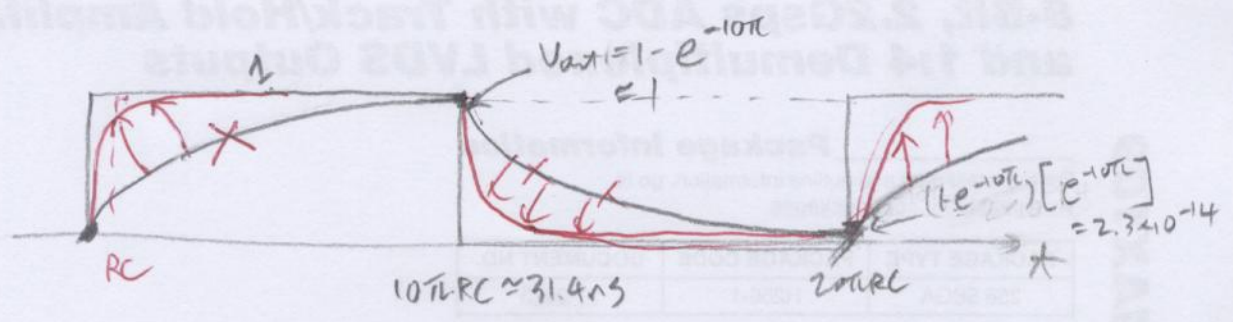
(iii)  $10\omega_c$



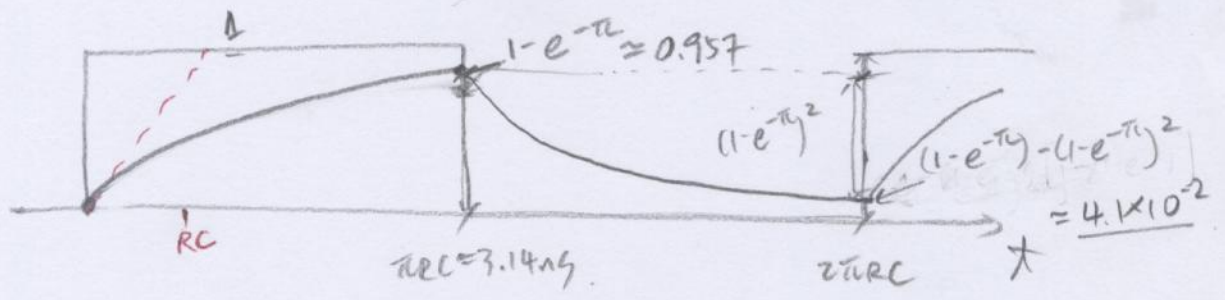
(c)  $H(s) = \frac{1}{1+RCs}$

$h(t) = 1 - e^{-\frac{1}{RC}t} = 1 - e^{-\omega_c t}$

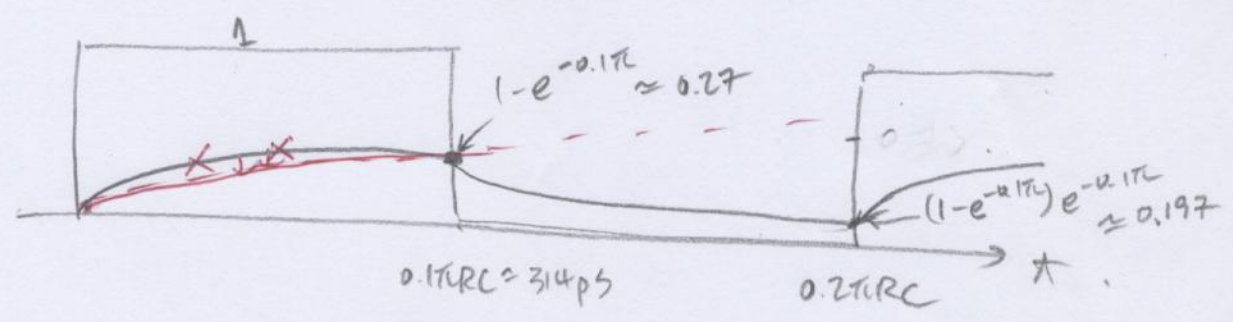
(i)  $0.1\omega_c$



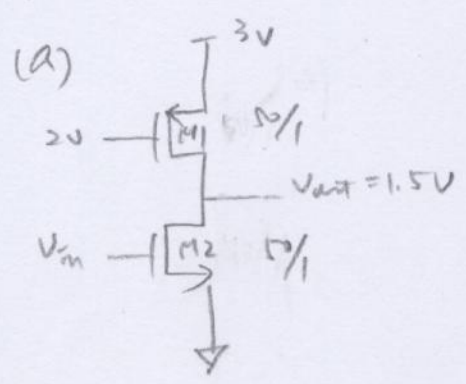
(ii)  $\omega_c$



(iii)  $10\omega_c$



[prob. 5]



$|V_{ds}| \geq |V_{gs}| - |V_{t,p}| = 0.5 \quad (\text{sat.})$

$$I_{D,p} = \frac{k_p}{2} \left(\frac{W}{L}\right) (|V_{gs}| - |V_{t,p}|)^2 (1 + \lambda |V_{ds}|)$$

$$= \frac{100\mu\text{A}/\text{V}^2}{2} \left(\frac{50}{1}\right) (0.5)^2 (1 + 0.1 \times 1.5)$$

$$= \underline{\underline{0.72\text{mA}}}$$



(b)  $I_{D,p} = I_{D,n}$  (a)  $V_{out} = 1.5V$

#9

$$\frac{K_p}{2} \left( \frac{W}{L} \right)_p (V_{GS,p} - V_{tp})^2 (1 + \lambda |V_{DS}|) \quad (\because \text{NMOS in sat.})$$

$$= \frac{K_n}{2} \left( \frac{W}{L} \right)_n (V_{GS,n} - V_{tn})^2 (1 + \lambda V_{DS})$$

$$\therefore (0.5)^2 = 2 \cdot (V_{GS,n} - 0.5)^2$$

$$V_{GS,n} = 0.5 \pm \frac{0.5}{\sqrt{2}} = \underline{\underline{0.85V}} \quad (\because V_{GS,n} > V_{th,n} \text{ to turn on})$$

(c)  $I_{m,n} = K_n \cdot \left( \frac{W}{L} \right) \cdot V_{GSAT} (1 + \lambda V_{DS})$

$$= 200 \mu A/\mu^2 \cdot \left( \frac{50}{1} \right) \cdot \frac{0.5}{\sqrt{2}} (1 + 0.1 \times 1.5)$$

$$= \underline{\underline{4.07 \text{ mA}}}$$

$$r_{o,n} = \frac{1 + \lambda V_{DS}}{\lambda I_D} = \frac{1 + 0.1 \times 1.5}{0.1 \times 0.72 \text{ mA}} = \underline{\underline{15.97 \text{ k}\Omega}}$$

$$I_{m,p} = 100 \mu A/\mu^2 \cdot \left( \frac{10}{1} \right) \cdot 0.5 \times (1 + 0.1 \times 1.5) = \underline{\underline{2.88 \text{ mA}}}$$

$$r_{o,p} = \frac{1 + 0.15}{0.1 \times 0.72 \text{ mA}} = \underline{\underline{15.97 \text{ k}\Omega}}$$

$$C_{gs,n} = \frac{2}{3} W L \cdot C_{ox} + W C_{ov}$$

$$= \frac{2}{3} \times 50 \mu\text{m} \times 1 \mu\text{m} \times 5 \text{ fF}/\mu\text{m}^2 + 50 \mu\text{m} \times 0.5 \text{ fF}/\mu\text{m}$$

$$= \underline{\underline{192.7 \text{ fF}}} = C_{gs,p}$$

$$C_{gd,n} = W \cdot C_{ov}' = \underline{\underline{25 \text{ fF}}} = C_{gd,p}$$

$$C_{db,n} = A D \cdot \frac{C_{db0}}{\sqrt{1 + \frac{V_D}{0.5}}} = \frac{50 \mu\text{m} \times 1 \mu\text{m} \times 1 \text{ fF}/\mu\text{m}^2}{2} = \underline{\underline{25 \text{ fF}}} = C_{db,p}$$

Both devices are in saturation.

(d)

	hand calc.	SPICE	% error
$I_D$	0.72mA	0.719mA	0.14%
$I_{m,n}$	4.07mS	4.07mS	0.10%
$I_{m,p}$	2.88mS	2.88mS	0.50%
$R_{o,n}$	15.97K $\Omega$	15.99K $\Omega$	0.16%
$R_{o,p}$	15.97K $\Omega$	16.00K $\Omega$	0.19%
$C_{gs}$	192.7fF	191.82fF	0.46%
$C_{db}$	<del>50.0fF</del> 25.0fF	<del>49.99fF</del> <del>25.0fF</del> 24.99fF	0.07 <sup>4</sup> %
$C_{gd}$	25.0fF	25.0fF	0.00%

For <sup>each</sup> the parameters, the % error should be less than 1%.

[Prob1(b)] MATLAB Code

```
options = optimset('TolFun', 1e-12);
[x, fval] = fminsearch(@(x) myfun(x), [100, 100 ], options)

function f = myfun(x)

gamma = x(1);
phi_f = x(2);

% NMOS
% measurement = [
% 0.65  0.75  0.8 ];
%approx = 0.45+ gamma *(sqrt(2*phi_f + [ 1 2 3 ]) - sqrt(2*phi_f));

% PMOS
measurement = [
0.7  0.8  0.9 ];
approx = 0.5+ gamma *(sqrt(2*phi_f + [ 1 2 3 ]) - sqrt(2*phi_f));

f = norm((approx-measurement) ./ approx)^2;
```

[Prob5 (c)]

```
* HW#2 prob5. PMOS-load NMOS common source amplifier
.param vtn=0.5
.param vtp=-0.5
.model nmos1 nmos vto='vtn'
+ tox=6.9nm kp=200u lambda=0.1 gamma=0.5 phi=0.6
+ capop=0 cgso=0.5n cgdo=0.5n pb=0.5 cj=1e-3
.model pmos1 pmos vto='vtp' tox=6.9nm kp=100u lambda=0.1 gamma=0.5 phi=0.6
+ capop=0 cgso=0.5n cgdo=0.5n pb=0.5 cj=1e-3

m1 out bias dd dd pmos1 w=50u l=1u AD=5e-11 AS=5e-11
m2 out in 0 0 nmos1 w=50u l=1u AD=5e-11 AS=5e-11

Vdd dd 0 3v
Vg in 0 dc 0.8536v
Vbias bias 0 2v

.options post
.op

.end
```

\*\*\*\* mosfets

```

subckt
element 0:m1 0:m2
model 0:pmos1 0:nmos1
region Saturati Saturati
id -718.8447u 718.8447u
ibs 0. 0.
ibd 15.0152f -14.9848f
vgs -1.0000 853.6000m
vds -1.5015 1.4985
vbs 0. 0.
vth -500.0000m 500.0000m
vdsat -500.0000m 353.6000m
vod -500.0000m 353.6000m
beta 5.7508m 11.4985m
gam eff 500.0000m 500.0000m
gm 2.8754m 4.0659m
gds 62.5000u 62.5165u
gmb 928.0246u 1.3123m
cdtot 49.9905f 50.0095f
cgtot 216.8194f 216.8194f
cstot 241.8194f 241.8194f
cbtot 74.9905f 75.0095f
cgs 191.8194f 191.8194f
cgd 25.0000f 25.0000f

```

$$= C_{gd} + C_{db}$$